

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10616525	FUNK ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Rutten, J. Derek	2192

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
717/127-130; 714/34,35 (Updated text search - see search history printout)	7/6/07	/jdr/
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT - see search history printout)	7/6/07	/jdr/
Tuan Dam, SPE 2192 and Wei Zhen, SPE 2191 (appeal conference)	5/16/08	/jdr/

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>